

Search Notes



Application/Control No.

10/032,729

Examiner

John L. Shew

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
370	347,352	4/24/2006	JS
	363,367		
	368,371		
	378,379		
	381,389		
	390,395,3		
	412,428		
	429		
708	232,273	4/24/2006	JS
709	230,236	4/24/2006	JS
	238,243		
	250		
710	310	4/24/2006	JS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
708	232,273	4/24/2006	JS

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
10/032,729	CHEN ET AL.	
	Art Unit	
	2616	